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F-7094

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Toru MATSUMOTO et al.
Serial No. : (Not yet known)
Filed : (Concurrently herewith)
For : SEMICONDUCTOR TEMPERATURE
DETECTING METHOD AND ITS CIRCUIT
Group Art Unit : (Not yet known)
Examiner : (Not yet known)

Assistant Commissioner
for Patents
Washington, D.C. 20231

PRELIMINARY AMENDMENT (A)

Sir:

Preliminary to examination, please amend the above-identified patent application as follows:

IN THE CLAIMS:

Please amend the claim as shown rewritten below with amendments effected therein. Appendix I is attached hereto having marked versions of said claim with amendments indicated by brackets and underlining.

FOI b7D b7E b7F b7G b7H b7I b7J b7K b7L b7M b7N b7O b7P b7Q b7R b7S b7T b7U b7V b7W b7X b7Y b7Z